







SN74AHCT244-Q1

SCLS529D - JULY 2003 - REVISED APRIL 2023

SN74AHCT244-Q1 Octal Buffer/Driver with 3-State Outputs

1 Features

- Qualified for automotive applications
- ESD protection exceeds 1000 V per MIL-STD-883, Method 3015; exceeds 200 V using Machine Model (C = 200 pF, R = 0)
- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs are TTL-Voltage compatible

2 Applications

- Enable or disable a digital signal
- Eliminate slow or noisy input signals
- Hold a signal during controller reset
- Debounce a switch

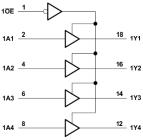
3 Description

This octal buffer/driver is designed specifically to improve both the performance and density of 3state memory-address drivers, clock drivers, and busoriented receivers and transmitters.

Table 3-1. Package Information⁽¹⁾

PART NUMBER		PACKAGE ⁽²⁾	BODY SIZE (NOM)
CNIZAALICTOAA OA	DW (SOIC, 20)	12.80 mm × 7.50 mm	
SN74AHCT244-Q1		PW (TSSOP, 20)	6.5 mm × 4.4 mm

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.
- Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.



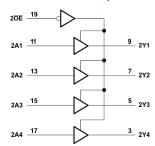


Figure 3-1. Logic Diagram (Positive Logic)



Table of Contents

1 Footures	9.4 Overview
1 Features1	8.1 Overview
2 Applications1	8.2 Functional Block Diagram
3 Description1	8.3 Device Functional Mode
4 Revision History2	9 Application and Implementation
5 Pin Configuration and Functions3	9.1 Power Supply Recommendations
Specifications4	9.2 Layout
6.1 Absolute Maximum Ratings4	10 Device and Documentation Support10
6.2 ESD Ratings4	10.1 Documentation Support10
6.3 Recommended Operating Conditions4	10.2 Receiving Notification of Documentation Updates 10
6.4 Thermal Information4	10.3 Support Resources10
6.5 Electrical Characteristics5	10.4 Trademarks10
6.6 Switching Characteristics5	10.5 Electrostatic Discharge Caution10
6.7 Noise Characteristics5	10.6 Glossary10
6.8 Operating Characteristics5	11 Mechanical, Packaging, and Orderable
7 Parameter Measurement Information6	Information10
B Detailed Description7	

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision C (April 2008) to Revision D (April 2023)

Page



5 Pin Configuration and Functions

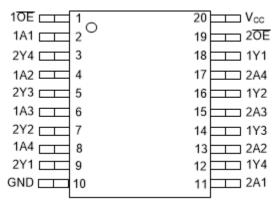


Figure 5-1. DW or PW Package (Top View)

Table 5-1. Pin Functions

PIN		1/0	DESCRIPTION
NO.	NAME	I/O	DESCRIPTION
1	1 OE	I	Output Enable 1
2	1A1	I	1A1 Input
3	2Y4	0	2Y4 Output
4	1A2	I	1A2 Input
5	2Y3	0	2Y3 Output
6	1A3	I	1A3 Input
7	2Y2	0	2Y2 Output
8	1A4	I	1A4 Input
9	2Y1	0	2Y1 Output
10	GND	_	Ground pin
11	2A1	I	2A1 Input
12	1Y4	0	1Y4 Output
13	2A2	I	2A2 Input
14	1Y3	0	1Y3 Output
15	2A3	I	2A3 Input
16	1Y2	0	1Y2 Output
17	2A4	I	2A4 Input
18	1Y1	0	1Y1 Output
19	2 OE	I	Output Enable 2
20	VCC		Power Pin



6 Specifications

6.1 Absolute Maximum Ratings

over Operating Free-air Temperature Range (Unless Otherwise Noted)

		MIN	MAX	UNIT
V _{CC}	Supply voltage range	-0.5	7	V
V _I ⁽¹⁾	Input voltage range	-0.5	7	V
V _O ⁽¹⁾	Output voltage range	-0.5	V _{CC} + 0.5	V
I _{IK} (V _I < 0)	Input clamp current		-20	mA
I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	Output clamp current		±20	mA
$I_O (V_O = 0 \text{ to } V_{CC})$	Continuous output current		±25	mA
	Continuous current through V _{CC} or GND		±75	mA
T _{stg}	Storage temperature range	-65	150	°C

(1) The input and output voltage ratings may be exceeded if the input and output current ratings are observed. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			MIN	MAX	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	0	1500	V
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	0	2000	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

(see (Note 1))

Ì	·		MIN	MAX	UNIT
V _{CC}	V _{CC} Supply voltage		4.5	5.5	V
V _{IH} High-level input voltage		2		V	
V _{IL} Low-level input voltage				0.8	V
VI	V _I Input voltage		0	5.5	V
Vo	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current			-8	mA
I _{OL}	Low-level output current			8	mA
т	O	I-suffix device	-40	85	°C
T _A	Operating free-air temperature	Q-suffix device	-40	125	C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		SN74AHC	SN74AHCT244-Q1		
		DW	PW	UNIT	
		20 P	INS		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.



6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	TA	= 25°C		MIN	MAY	UNIT
PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	IVIIIN	MAX	UNII
V	I _{OH} = -50 mA	4.5 V	4.4	4.5		4.4		V
V _{OH}	I _{OH} = -8 mA	4.5 V	3.94			3.8		V
V	I _{OL} = 50 mA	4.5 V			0.1		0.1	V
V_{OL}	I _{OL} = 8 mA	4.5 V			0.36		0.44	'
I _{OZ}	V _O = V _{CC} or GND	5.5 V			±0.25		±2.5	μA
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			±0.1		±1	μA
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40	μA
ΔI _{CC} ⁽¹⁾	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			1.35	1.5		μΑ
Ci	V _I = V _{CC} or GND	5 V		2.5	10			pF
Co	V _O = V _{CC} or GND	5 V		3				pF

⁽¹⁾ This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V_{CC} .

6.6 Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM (INPUT) TO (OUTPU	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C		MIN	MAX	UNIT	
PARAMETER	FROW (INPUT)	10 (001P01)		MIN TYP	MAX	IVIIIN	WAX	UNII	
t _{PLH}	А	Y	C _L = 15 pF	5.4	7.4	1	8.5	ns	
t _{PHL}	A	I	О_ – 13 рг	5.4	7.4	1	8.5	115	
t _{PZH}	ŌĒ	E Y C _L = 15 pF —	7.7	10.4	1	12	ns		
t _{PZL}	OE		$C_L = 15 \text{ pF}$	C _L = 15 pF	7.7	10.4	1	12	115
t _{PHZ}	- OE Y	V	C _L = 15 pF	5	9.4	1	10	ns	
t _{PLZ}		C _L = 13 μr	5	9.4	1	10) 118		
t _{PLH}	A	Y	C _L = 50 pF	5.9	8.4	1	9.5	ns	
t _{PHL}	A	1 CL =	ι ΘΕ σο μι	5.9	8.4	1	9.5	115	
t _{PZH}	ŌĒ	V	C _L = 50 pF	8.2	11.4	1	13	no	
t _{PZL}	OE	ŌĒ Y		CL = 30 βF	8.2	11.4	1	13	ns
t _{PHZ}	ŌĒ	Y	C _L = 50 pF	8.8	11.4	1	13	nc	
t _{PLZ}	OE .	OE Y CL=	OL = 50 pr	8.8	11.4	1	13	ns	
t _{sk(o)}			C _L = 50 pF		1			ns	

6.7 Noise Characteristics

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C (see (Note 1))}$

	PARAMETER	MIN	TYP	MAX	UNIT
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.1		V
V _{IH(D)}	High-level dynamic input voltage	2			V
V _{IL(D)}	Low-level dynamic input voltage			0.8	V

⁽¹⁾ Characteristics are for surface-mount packages only.

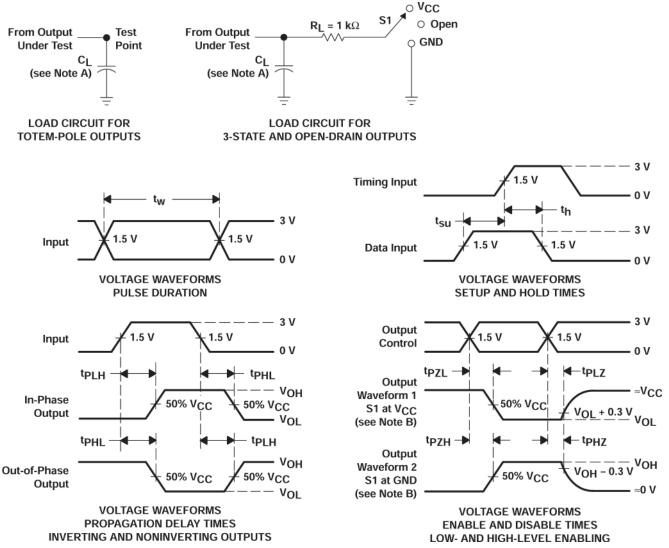
6.8 Operating Characteristics

 V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load, f = 1 MHz	8.2	pF



7 Parameter Measurement Information



- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
- D. The outputs are measured one at a time, with one input transition per measurement.

Figure 7-1. Load Circuit and Voltage Waveforms

TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	V _{CC}
t _{PHZ} /t _{PZH}	GND
Open Drain	V _{CC}

8 Detailed Description

8.1 Overview

The SN74AHCT244 is organized as two 4-bit buffers/line drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} shall be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

8.2 Functional Block Diagram

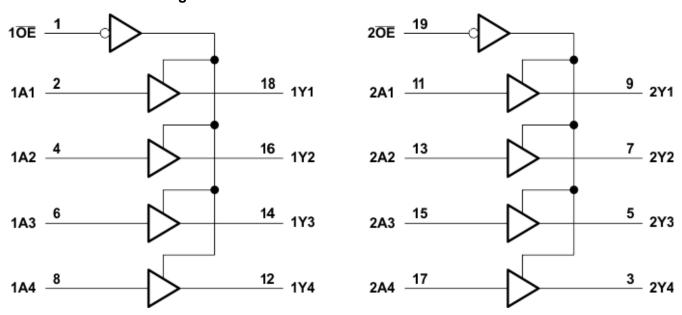


Figure 8-1. Logic Diagram (Positive Logic)

8.3 Device Functional Mode

Table 8-1. (Each 4-Bit Buffer/Driver)

INP	INPUTS					
ŌĒ	Α	OUTPUT Y				
L	Н	Н				
L	L	L				
Н	X	Z				



9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the Section 6.3 table.

Each VCC pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, 0.1 μ f is recommended; if there are multiple VCC pins, then 0.01 μ f or 0.022 μ f is recommended for each power pin. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. A 0.1 μ f and a 1 μ f are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

9.2 Layout

9.2.1 Layout Guidelines

When using multiple-bit logic devices, inputs should never float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Section 9.2.1.1 specifies the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} , whichever makes more sense or is more convenient. It is generally acceptable to float outputs, unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the output section of the part when asserted. This will not disable the input section of the I/Os, so they cannot float when disabled.



9.2.1.1 Layout Example

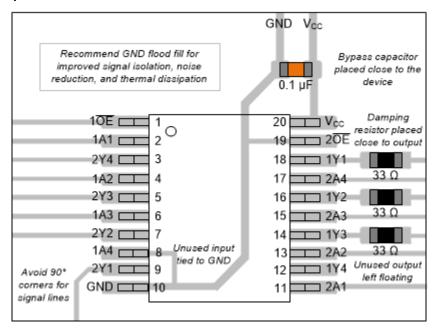


Figure 9-1. Layout Diagram

10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 10-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY	
SN74AHCT244-Q1	Click here	Click here	Click here	Click here	Click here	

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

www.ti.com 17-Apr-2023

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CAHCT244IPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I	Samples
CAHCT244QDWRG4Q1	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q	Samples
CAHCT244QPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q	Samples
SN74AHCT244IPWRQ1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I	Samples
SN74AHCT244QDWRQ1	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q	Samples
SN74AHCT244QPWRQ1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

PACKAGE OPTION ADDENDUM

www.ti.com 17-Apr-2023

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74AHCT244-Q1:

Catalog: SN74AHCT244

Enhanced Product: SN74AHCT244-EP

Military: SN54AHCT244

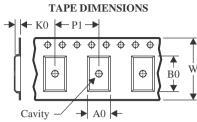
NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications

www.ti.com 17-Apr-2023

TAPE AND REEL INFORMATION

REEL DIMENSIONS Reel Diameter Reel Width (W1)



A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

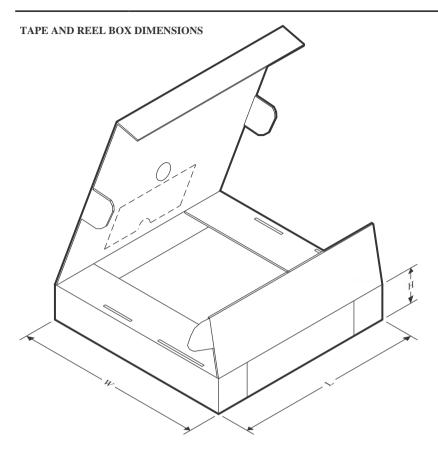


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
CAHCT244QDWRG4Q1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CAHCT244QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74AHCT244IPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74AHCT244QDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74AHCT244QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1



www.ti.com 17-Apr-2023



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0
CAHCT244QDWRG4Q1	SOIC	DW	20	2000	367.0	367.0	45.0
CAHCT244QPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0
SN74AHCT244IPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0
SN74AHCT244QDWRQ1	SOIC	DW	20	2000	367.0	367.0	45.0
SN74AHCT244QPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated